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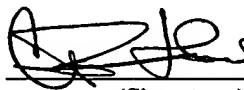
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Seiichi HAYASHI, et al.
Serial No. : 09/852,111
Filed : May 9, 2001
For : METHOD AND APPARATUS FOR MEASURING
THIN FILM, AND THIN FILM DEPOSITION
SYSTEM
Group Art Unit : 2882
Examiner : Hoon K. Song

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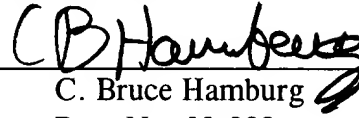
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Respectfully submitted,

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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				Applicant: Seiichi HAYASHI, et al.			
				Filing Date: May 9, 2001		Group: 2882	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
TRANSLATION KEY: * English Abstract. ^F Concise statement of relevance provided in foreign search report. ^C Concise statement of relevance provided in specification. ^S Concise statement of relevance provided in IDS. ^P Relevant portion of reference translated. ^O English abstract only - copy of reference in pct search.							
OTHER INFORMATION DISCLOSURE CITATIONS (Including Author, Title, Date, Pertinent Pages, Etc.)							
		1997 - X-ray Reflectometer for the Diagnostics of Thin Films During Growth, U. Niggemeier, K. Lischka, W. M. Plotz and V. Holy, Journal of Applied Crystallography, Volume 30, Pages 905-908					
EXAMINER Hoon K. Song				DATE CONSIDERED			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							